


<b>Search Notes</b>  	<b>Application/Control No.</b>  10553802	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA ET AL.
	<b>Examiner</b>  PHILIP H LEUNG	<b>Art Unit</b>  3742

SEARCHED			
Class	Subclass	Date	Examiner
219	639, 640, 635, 672, 674, 676	updated	P.L.
266	129	3-4-2008	
148	572-573		

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner